

<b>Notice of References Cited</b>	Application/Control No. 10/822,373	Applicant(s)/Patent Under Reexamination YAMANAKA ET AL.	
	Examiner Kezhen Shen	Art Unit 2609	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0196776 A1	10-2004	Yoshida et al.	369/275.1
*	B	US-2003/0137914 A1	07-2003	Kashihara et al.	369/59.22
*	C	US-2004/0174802 A1	09-2004	Suzuki, Yuichi	369/275.3
*	D	US-2002/0006084 A1	01-2002	Kawashima et al.	369/30.1
*	E	US-2003/0161254 A1	08-2003	Blankenbeckler et al.	369/275.3
*	F	US-2003/0012099 A1	01-2003	Sako et al.	369/47.23
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.